



Initial Product/Process Change Notification

Document #: IPCN26343Z

Issue Date: 09 Jul 2026

Title of Change:	Qualification for SO8FL and u8FL Package from Mold Compound G700LS to G700LAE						
Proposed Changed Material First Ship Date:	29 May 2027 or earlier if approved by customer						
Current Material Last Order Date:	NA <i>Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.</i>						
Current Material Last Delivery Date:	NA <i>The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory.</i>						
Product Category:	Active components – Discrete components						
Contact information:	Contact your local onsemi Sales Office						
PCN Samples Contact:	Contact your local onsemi Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.						
Additional Reliability Data:	Contact your local onsemi Sales Office						
Type of Notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 6 months prior to implementation of the change. In case of questions, contact < PCN.Support@onsemi.com >						
Change Category							
Category	Type of Change						
Process - Assembly	SEM-PA-11: Change of mold compound / encapsulation material						
Description and Purpose:							
onsemi wishes to inform customers of its plan to change the mold compound used in SO8FL and u8FL packages from G700LS to G700LAE at the onsemi Seremban, Malaysia manufacturing site. This change is being implemented to improve delamination performance after preconditioning.							
<table><tr><th>Item change</th><th>From</th><th>To</th></tr><tr><td>Mold Compound</td><td>G700LS</td><td>G700LAE</td></tr></table>		Item change	From	To	Mold Compound	G700LS	G700LAE
Item change	From	To					
Mold Compound	G700LS	G700LAE					
There are no product material changes as a result of this change and no product marking change as a result of this change.							
There is no product marking change as a result of this change							
Reason / Motivation for Change:	Process/Materials Change						
Anticipated impact on fit, form, function, reliability, product safety or manufacturability:	The device will be qualified and validated based on the same Product Specification. No anticipated impacts.						

Sites Affected:

onsemi Sites

onsemi Seremban, Malaysia

External Foundry/Subcon Sites

None

Marking of Parts/ Traceability of Change:

No change

Qualification Plan:

QV DEVICE NAME : NVMFD6H840NLT1G

RMS: 101329

PACKAGE: SO8FL Dual (T8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFD040N10MCLT1G

RMS: 102365

PACKAGE: SO8FL Dual (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS3D6N10MCLT1G

RMS: 101197

PACKAGE: SO8FL HD (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS5C604NLAFT1G

RMS: 101842

PACKAGE: SO8FL HD (T6)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS6H800NWFT1G

RMS: 104471

PACKAGE: SO8FL HD (T8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS6H850NLWFTAG

RMS: 104474

PACKAGE: u8FL (T8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS9D6P04M8LTAG

RMS: 102571

PACKAGE: u8FL (MV8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : MBR8170TFSTXG

RMS: 102572

PACKAGE: u8FL (Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NTMFS002P03P8ZST1G

RMS: 104088

PACKAGE: SO8FL HD (PT8P)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=150°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRVB30H100MFST3G

RMS: 102309

PACKAGE: SO8FL HD (Schottky Planar)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRVTS30120MFST3G

RMS: 107925

PACKAGE: SO8FL HD (Trench Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS5832NLWFT1G

RMS: 105752

PACKAGE: SO8FL HD (T2)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMF55113PLWFT1G

RMS: 107924

PACKAGE: SO8FL HD (T1)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : MBR30170MFST1G

RMS: 110767

PACKAGE: SO8FL HD (Schottky Diode)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS015P03P8ZTAG

RMS: 106678

PACKAGE: u8FL (PT8P)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS002N04CLTAG

RMS: 106421

PACKAGE: u8FL (T6)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS027N10MCLTAG

RMS: 106696

PACKAGE: u8FL (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS010N10MCLTAG

RMS: 106696

PACKAGE: u8FL (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS5116PLWFTAG

RMS: 105753

PACKAGE: u8FL (T1)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRVHP820MFD1G

RMS: TBD

PACKAGE: SO8FL Dual (Rect Ultrafast)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFD5873NLWFT1G-UM

RMS: TBD

PACKAGE: SO8FL Dual (T2)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFD5C650NLT1G-01

RMS: TBD

PACKAGE: SO8FL Dual (T6)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NTMFS0D8N02P1ET1G

RMS: TBD

PACKAGE: SO8FL HD (PT11E)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS9D6P04M8LT1G

RMS: TBD

PACKAGE: SO8FL HD (MV8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS5826NLWFTWG

RMS: TBD

PACKAGE: u8FL (T2)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRTS6100TFSTAG

RMS: TBD

PACKAGE: u8FL (Trench Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRVTS30120MFST3G

RMS: 107925

PACKAGE: SO8FL HD (Trench Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

Estimated date for qualification completion: **1 August 2026**

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

Current Part Number	New Part Number	Qualification Vehicle
NVMFD5C478NT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C470NT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C466NT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C650NLWFT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C650NLET1G	#NONE	NVMFD5C650NLT1G
NRVHP620MFDT3G	#NONE	NRVHP820MFDT1G
NVMFD5C462NLWFT1G	#NONE	NVMFD5C650NLT1G
NVMFD040N10MCLT1G	#NONE	NVMFD040N10MCLT1G
NVMFD5C446NLT1G	#NONE	NVMFD5C650NLT1G
NVMFD5873NLWFT1G	#NONE	NVMFD5873NLWFT1G



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NVMFD5C462NLT1G	#NONE	NVMFD5C650NLT1G
NVMFD027N10MCLT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C462NT1G	#NONE	NVMFD5C650NLT1G
NRVHP620MFD1G	#NONE	NRVHP820MFD1G
NVMFD5C470NWFT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C478NLT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C478NLWFT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C672NLT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C672NLWFT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C674NLT1G	#NONE	NVMFD5C650NLT1G
NVMFWD040N10MCLT1G	#NONE	NVMF53D6N10MCLT1G
NVMFWD030N06CT1G	#NONE	NVMF53D6N10MCLT1G
NVMFWD027N10MCLT1G	#NONE	NVMF53D6N10MCLT1G
NVMFWD024N06CT1G	#NONE	NVMFD5C650NLT1G
NVMFWD020N10MCLT1G	#NONE	NVMFD5C650NLT1G
NVMFWD020N06CT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C680NLET1G	#NONE	NVMFD5C650NLT1G
NVMFD5C674NLWFT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C478NWFT1G	#NONE	NVMFD5C650NLT1G
NVMFD5C470NLWFET1G	#NONE	NVMFD5C650NLT1G
NVMFD5C470NLET1G	#NONE	NVMFD5C650NLT1G
NVMFD5C466NLWFET1G	#NONE	NVMFD5C650NLT1G
NVMFD5C466NLET1G	#NONE	NVMFD5C650NLT1G
NVMFD5C446NT1G	#NONE	NVMFD5C650NLT1G
NVMFD5877NLT1G	#NONE	NVMFD5873NLWFT1G
NVMFD030N06CT1G	#NONE	NVMFD5C650NLT1G
NVMFD024N06CT1G	#NONE	NVMFD5C650NLT1G
NVMFD020N10MCLT1G	#NONE	NVMFD5C650NLT1G
NVMFD020N06CT1G	#NONE	NVMFD5C650NLT1G
NVMFD016N06CT1G	#NONE	NVMFD5C650NLT1G
NVMFD010N10MCLT1G	#NONE	NVMFD5C650NLT1G
NRVHP820MFD1G	#NONE	NRVHP820MFD1G
NRVHP420MFDWFT3G	#NONE	NRVHP820MFD1G
NRVHP420MFD1G	#NONE	NRVHP820MFD1G
NVMFWD010N10MCLT1G	#NONE	NVMFD5C650NLT1G



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NVMFWD016N06CT1G	#NONE	NVMFD5C650NLT1G
NRVHP420MFDT3G	#NONE	NRVHP820MFDT1G
NVMFD5C680NLWFET1G	#NONE	NVMFD5C650NLT1G

PCN Product List Addendum for:

Customer Contact Name: Premier Farnell Dropbox

Customer Contact Email: productchangenotices@newark.com

Appendix A: Changed Products

PCN#: IPCN26343Z
Issue Date: Jul 09, 2026

NWKC: PREMIER FARNELL

Product	Customer Part Number	Qualification Vehicle	New Part Number	Replacement Supplier
NVMFD5C650NLWFT1G	2835607	NVMFD5C650NLT1G	#NONE	
NVMFD5C462NLWFT1G	2835601	NVMFD5C650NLT1G	#NONE	
NVMFD5C446NLT1G	2835598	NVMFD5C650NLT1G	#NONE	
NVMFD5C672NLT1G	2835608	NVMFD5C650NLT1G	#NONE	
NVMFD5C478NT1G	2895745	NVMFD5C650NLT1G	#NONE	
NVMFD027N10MCLT1G	4317982	NVMFD5C650NLT1G	#NONE	
NVMFD5C446NT1G	2895698	NVMFD5C650NLT1G	#NONE	
NVMFD5C674NLT1G	2835610	NVMFD5C650NLT1G	#NONE	